

Sub B
Sub A
Cut

further comprising the step of forming, on the electrode, a dielectric film for a capacitor after the step b) has been performed.

12. (Amended) The method of Claim 11, wherein the step b) is performed in an atmosphere that contained hydrogen and that has been created as the reducing atmosphere.

Please add the following new claims:

AA
Sub B

--16. (New) The method of Claim 11, wherein the electrode is composed of Pt.

17. (New) The method of Claim 11, wherein the electrode is composed of Ir.

18. (New) The method of Claim 11, wherein the electrode is composed of Ru.

19. (New) The method of Claim 11, wherein the electrode is composed of Rh.

20. (New) The method of Claim 13, wherein the electrode is composed of Pt.

21. (New) The method of Claim 13, wherein the electrode is composed of Ir.

22. (New) The method of Claim 13, wherein the electrode is composed of Ru.

23. (New) The method of Claim 13, wherein the electrode is composed of Rh.

24. (New) The method of Claim 11, wherein the dielectric film is composed of BST.✓

25. (New) The method of Claim 11, wherein the dielectric film is composed of SBT.✓

26. (New) The method of Claim 11, wherein the dielectric film is composed of PZT.

27. (New) The method of Claim 11, wherein the dielectric film is composed of Ta_2O_5 .✓

28. (New) The method of Claim 13, wherein the dielectric film is composed of BST.

29. (New) The method of Claim 13, wherein the dielectric film is composed of SBT.

30. (New) The method of Claim 13, wherein the dielectric film is composed of PZT.

31. (New) The method of Claim 13, wherein the dielectric film is composed of Ta_2O_5 .

32. (New) The method of Claim 11, wherein the electrode is composed of Ru and the dielectric film is composed of Ta_2O_5 .

33. (New) The method of Claim 11, wherein the electrode is composed of Ir and the dielectric film is composed of SBT.

34. (New) The method of Claim 11, wherein the electrode is composed of Ir and the dielectric film is composed of PZT.

35. (New) The method of Claim 13, wherein the electrode is composed of Ru and the dielectric film is composed of Ta_2O_5 .

36. (New) The method of Claim 13, wherein the electrode is composed of Ir and the dielectric film is composed of SBT.

37. (New) The method of Claim 13, wherein the electrode is composed of Ir and the dielectric film is composed of PZT.--

REMARKS

At the outset the Examiner is thanked for the review and consideration of the present application. Filed concurrently herewith is a Request for a One-Month Extension of Time which extends the shortened statutory period for response to November 1, 2002. Accordingly, Applicants respectfully submit that this response is being timely filed.

The Examiner's Action dated July 1, 2002 has been received and its contents reviewed.